

Notice of References Cited	Application/Control No. 10/576,990		Applicant(s)/Patent Under Reexamination HICKS, R. ANDREW	
	Examiner JOHN M. VILLECCO		Art Unit 2622	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2007/0263113	11-2007	BAEK et al.	348/340
*	B	US-2007/0040924	02-2007	Cho et al.	348/335
*	C	US-7,339,746	03-2008	Kim et al.	359/676
*	D	US-7,173,653	02-2007	Gim et al.	348/335
*	E	US-2007/0171292	07-2007	Kondo et al.	348/294
*	F	US-6,473,122	10-2002	Kanekal, Hemanth G.	348/340
*	G	US-2005/0206737	09-2005	Gim et al.	348/208.11
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 2002228425 A	08-2002	Japan	MORIMOTO et al.	
	O	JP 2005005975 A	01-2005	Japan	MARUNO, HIROMASA	
	P	WO 2006050430 A2	05-2006	World Intellect	KIM et al.	
	Q	JP 11231373 A	08-1999	Japan	SAITO et al.	
	R	JP 11069209 A	03-1999	Japan	MATSUDA, SHINYA	
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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